

# IR2136/IR21362

## Features

- Floating channel designed for bootstrap operation
- Fully operational to +600V
- Tolerant to negative transient voltage  
dV/dt immune
- Gate drive supply range from 10 to 20V (IR2136) or 12 to 20V (IR21362)
- Undervoltage lockout for all channels
- Over-current shutdown turns off all six drivers
- Independent 3 half-bridge drivers
- Matched propagation delay for all channels
- Lowside outputs out of phase with inputs. High side outputs out of phase (IR2136) or in phase (IR21362) with inputs.
- 5V Schmitt-triggered input logic
- Cross-conduction prevention logic
- Lower di/dt gate driver for better noise immunity
- Externally programmable delay for automatic fault clear

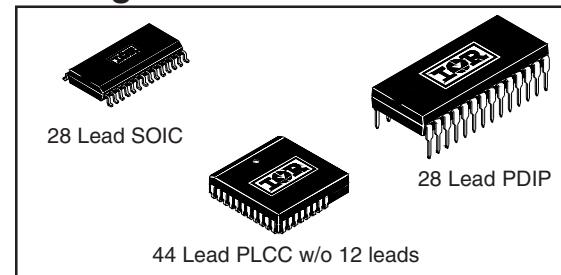
## Description

The IR2136/IR21362 are high voltage, high speed power MOSFET and IGBT drivers with three independent high and low side referenced output channels for 3-phase applications. Proprietary HVIC technology enables ruggedized monolithic construction. Logic inputs are compatible with 5V CMOS or LSTTL outputs. A current trip function which terminates all six outputs can be derived from an external current sense resistor. An enable function is available to terminate all six outputs simultaneously. An open-drain FAULT signal is provided to indicate that an overcurrent or undervoltage

## Product Summary

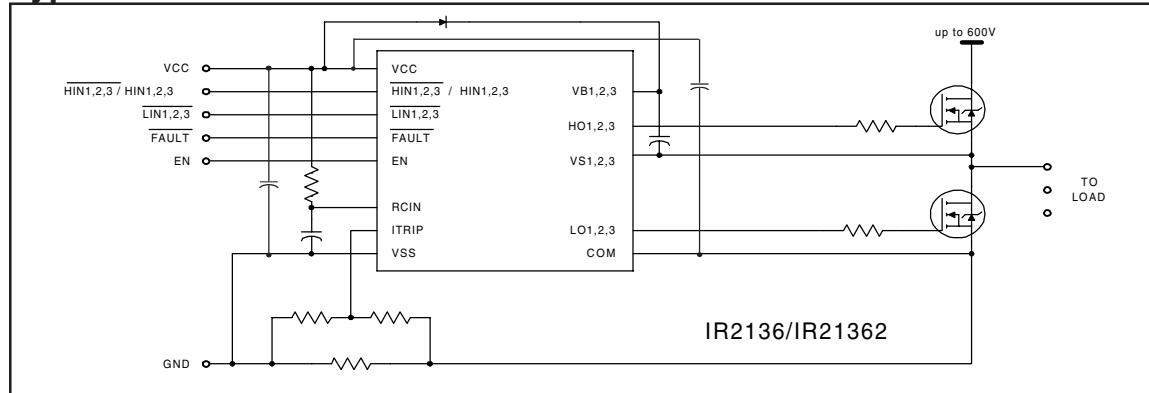
V <sub>OFFSET</sub>	600V max.
I <sub>O+/-</sub>	120 mA / 250 mA
V <sub>OUT</sub>	10 - 20V or 12V - 20V
Deadtime (typ.)	200 nsec
t <sub>on/off</sub> (typ.)	400 nsec

## Packages



shutdown has occurred. Overcurrent fault conditions are cleared automatically after a delay programmed externally via an RC network connected to the RCIN input. The output drivers feature a high pulse current buffer stage designed for minimum driver cross-conduction. Propagation delays are matched to simplify use in high frequency applications. The floating channel can be used to drive N-channel power MOSFETs or IGBTs in the high side configuration which operates up to 600 volts.

## Typical Connection



**Absolute Maximum Ratings**

Absolute maximum ratings indicate sustained limits beyond which damage to the device may occur. All voltage parameters are absolute voltages referenced to COM. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions.

Symbol	Definition	Min.	Max.	Units
$V_S$	High side offset voltage	-0.3	600	V
$V_{BS}$	High side floating supply voltage	-0.3	25	
$V_{HO}$	High side floating output voltage	$V_{S1,2,3} - 0.3$	$V_{B1,2,3} + 0.3$	
$V_{CC}$	Low side and logic fixed supply voltage	-0.3	25	
$V_{SS}$	Logic ground	$V_{CC} - 25$	$V_{CC} + 0.3$	
$V_{LO1,2,3}$	Low side output voltage	-0.3	$V_{CC} + 0.3$	
$V_{IN}$	Input voltage $\overline{LIN}, \overline{HIN}$ (IR2136), $HIN$ (IR21362) ITRIP, EN, RCIN	$V_{SS} - 0.3$	$V_{CC} + 0.3$	
$V_{FLT}$	FAULT output voltage	$V_{SS} - 0.3$	$V_{CC} + 0.3$	
$dV/dt$	Allowable offset voltage slew rate	—	50	V/ns
$P_D$	Package power dissipation @ $T_A = +25^\circ\text{C}$	—	1.5	W
	(28 lead PDIP)	—	1.6	
	(44 lead PLCC)	—	2.0	
$R_{thJA}$	Thermal resistance, junction to ambient	—	83	$^\circ\text{C}/\text{W}$
	(28 lead SOIC)	—	78	
	(44 lead PLCC)	—	63	
$T_J$	Junction temperature	—	150	$^\circ\text{C}$
$T_S$	Storage temperature	-55	150	
$T_L$	Lead temperature (soldering, 10 seconds)	—	300	

**Recommended Operating Conditions**

The Input/Output logic timing diagram is shown in figure 1. For proper operation the device should be used within the recommended conditions. All voltage parameters are absolute referenced to COM. The  $V_S$  offset rating is tested with all supplies biased at 15V differential.

Symbol	Definition	Min.	Max.	Units
$V_{B1,2,3}$	High side floating supply voltage	$V_{S1,2,3} + 10$	$V_{S1,2,3} + 20$	V
$V_{S1,2,3}$	High side floating supply offset voltage	Note 1	600	
$V_{HO1,2,3}$	High side output voltage	$V_{S1,2,3}$	$V_{B1,2,3}$	
$V_{LO1,2,3}$	Low side output voltage	0	$V_{CC}$	
$V_{CC}$	Low side and logic fixed supply voltage	10	20	
$V_{SS}$	Logic ground	-5	5	
$V_{FLT}$	FAULT output voltage	$V_{SS}$	$V_{CC}$	
$V_{RCIN}$	RCIN input voltage	$V_{SS}$	$V_{CC}$	
$V_{ITRIP}$	ITRIP input voltage	$V_{SS}$	$V_{SS} + 5$	
$V_{IN}$	Logic input voltage $\overline{LIN}, \overline{HIN}$ (IR2136), $HIN$ (IR21362), EN	$V_{SS}$	$V_{SS} + 5$	
$T_A$	Ambient temperature	-40	125	$^\circ\text{C}$

Note 1: Logic operational for  $V_S$  of COM -5 to COM +600V. Logic state held for  $V_S$  of COM -5V to -COM - $V_{BS}$ .

## Static Electrical Characteristics

$V_{BIAS}$  ( $V_{CC}$ ,  $V_{BS1,2,3}$ ) = 15V and  $T_A = 25^\circ C$  unless otherwise specified. The  $V_{IN}$ ,  $V_{TH}$  and  $I_{IN}$  parameters are referenced to  $V_{SS}$  and are applicable to all six channels ( $H_S1,2,3$  and  $L_S1,2,3$ ). The  $V_O$  and  $I_O$  parameters are referenced to COM and  $V_{S1,2,3}$  and are applicable to the respective output leads:  $H_{O1,2,3}$  and  $L_{O1,2,3}$ .

Symbol	Definition	Min.	Typ.	Max.	Units	Test Conditions
$V_{IH}$	Logic "0" input voltage $LIN1,2,3$ , $HIN1,2,3$	2.7	—	—	V	
	Logic "1" input voltage $HIN1,2,3$					
$V_{IL}$	Logic "1" input voltage $LIN1,2,3$ , $HIN1,2,3$	—	—	0.8		
	Logic "0" input voltage $HIN1,2,3$					
$V_{EN,TH+}$	EN positive going threshold	—	—	2.7		
$V_{EN,TH-}$	EN negative going threshold	0.8	—	—		
$V_{IT,TH+}$	ITRIP positive going threshold	—	480	—		mV
$V_{IT,HYS}$	ITRIP input hysteresis	—	80	—		
$V_{RCIN,TH+}$	RCIN positive going threshold	—	8	—		
$V_{RCIN,HYS}$	RCIN input hysteresis	—	3	—		
$V_{OH}$	High level output voltage, $V_{BIAS} - V_O$	—	0.8	1.4	V	$I_O = 20 \text{ mA}$
$V_{OL}$	Low level output voltage, $V_O$	—	0.3	0.6		$I_O = 20 \text{ mA}$
$V_{CCUV+}$	$V_{CC}$ and $V_{BS}$ supply undervoltage positive going threshold	IR2136	8.0	8.9		
$V_{BSUV+}$	IR21362	9.6	10.4	11.2		
$V_{CCUV-}$	$V_{CC}$ and $V_{BS}$ supply undervoltage negative going threshold	IR2136	7.4	8.2		
$V_{BSUV-}$	IR21362	8.6	9.4	10.2		
$V_{CCUVH}$	$V_{CC}$ and $V_{BS}$ supply undervoltage lockout hysteresis	IR2136	0.3	0.7		
$V_{BSUVH}$	IR21362	0.5	1.0	—		
$I_{LK}$	Offset supply leakage current	—	—	50	$\mu\text{A}$	$V_{B1,2,3}=V_{S1,2,3}=600\text{V}$
$I_{QBS}$	Quiescent $V_{BS}$ supply current	20	60	150		$V_{IN} = 0\text{V or } 5\text{V}$
$I_{QCC}$	Quiescent $V_{CC}$ supply current	—	1	2		
$I_{IN+}$	Input bias current ( $OUT = HI$ or $OUT = LO$ )	—	120	—		
$I_{ITRIP+}$	"high" ITRIP input bias current	—	100	—		$V_{ITRIP} = 5\text{V}$
$I_{ITRIP-}$	"low" ITRIP input bias current	—	0	1		$V_{ITRIP} = 0\text{V}$
$I_{EN+}$	"high" ENABLE input bias current	—	100	—		$V_{ENABLE} = 5\text{V}$
$I_{EN-}$	"low" ENABLE input bias current	—	0	1		$V_{ENABLE} = 0\text{V}$
$I_{RCIN}$	RCIN input bias current	—	0	1		$V_{RCIN} = 0\text{V or } 15\text{V}$
$I_{O+}$	Output high short circuit pulsed current	120	200	—	$\text{mA}$	$V_O = 0\text{V}, PW \leq 10 \mu\text{s}$
$I_{O-}$	Output low short circuit pulsed current	250	350	—		$V_O = 15\text{V}, PW \leq 10 \mu\text{s}$
$R_{ON,RCIN}$	RCIN low on resistance	—	60	—	$\text{W}$	
$R_{ON,FLT}$	FAULT low on resistance	—	60	—		

**Dynamic Electrical Characteristics**

$V_{CC} = V_{BS} = V_{BIAS} = 15V$ ,  $V_{S1,2,3} = V_{SS} = COM$ ,  $T_A = 25^{\circ}C$  and  $C_L = 1000 \text{ pF}$  unless otherwise specified.

Symbol	Definition	Min.	Typ.	Max.	Units	Test Conditions
$t_{on}$	Turn-on propagation delay	—	400	—	nS	$V_{IN} = 0 \& 5V$ $V_{S1,2,3} = 0 \text{ to } 600V$
$t_{off}$	Turn-off propagation delay	—	380	—		$V_{IN}, V_{EN} = 0V \text{ or } 5V$
$t_r$	Turn-on rise time	—	110	—		$V_{IN} = 0V \text{ or } 5V$ $V_{ITRIP} = 5V$
$t_f$	Turn-off fall time	—	50	—		$V_{IN} = 0V \text{ or } 5V$ $V_{ITRIP} = 5V$
$t_{EN}$	ENABLE low to output shutdown propagation delay	—	400	—		$V_{IN} = 0 \& 5V$
$t_{ITRIP}$	ITRIP to output shutdown propagation delay	—	700	—		$V_{IN} = 0V \text{ or } 5V$ $V_{ITRIP} = 5V$
$t_{bl}$	ITRIP blanking time	100	150	—		$V_{IN} = 0V \text{ or } 5V$ $V_{ITRIP} = 5V$
$t_{FLT}$	ITRIP to FAULT propagation delay	—	500	—		$V_{IN} = 0V \text{ or } 5V$ $V_{ITRIP} = 5V$
$t_{FILIN}$	Input filter time (HIN, LIN, EN)	100	200	—		$V_{IN} = 0 \& 5V$
$t_{FLTCLR}$	FAULT clear time RCIN: $R=2\text{meg}$ , $C=1\text{nF}$	—	1.8	—	mS	$V_{IN} = 0V \text{ or } 5V$ $V_{ITRIP} = 0V$
DT	Deadtime	—	250	—		$V_{IN} = 0 \& 5V$
MT	Matching delay ON and OFF	—	0	80		
MDT	Matching delay, max ( $t_{on}, t_{off}$ ) - min ( $t_{on}, t_{off}$ ), ( $t_{on}, t_{off}$ are applicable to all 3 channels)	—	0	75		External dead time >400nsec
PM	Output pulse width matching, PWin - PWout (fig.2)	—	0	75		

NOTE: For high side PWM, HIN pulse width must be  ${}^3 1\text{msec}$

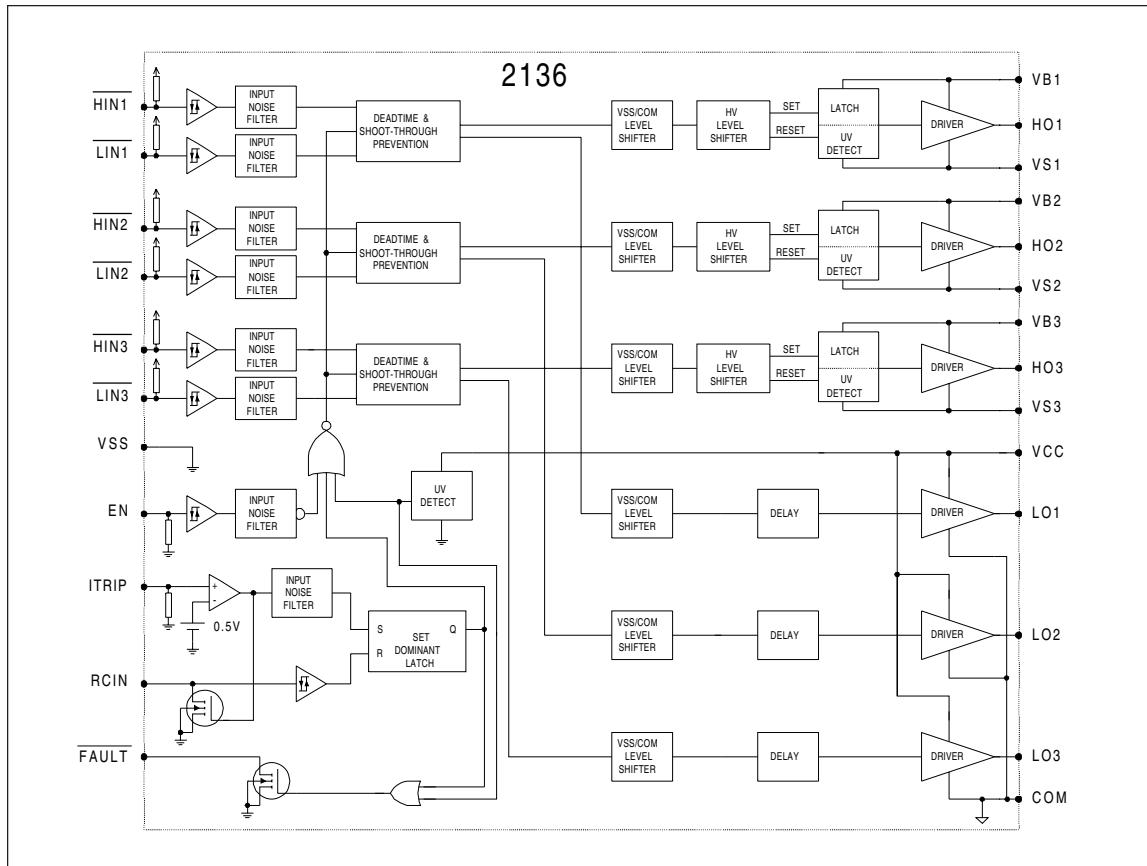
VCC	VBS	ITRIP	ENABLE	FAULT	LO1,2,3	HO1,2,3
<UVCC	X	X	X	0 (note 1)	0	0
15V	<UVBS	0V	5V	high imp	LIN1,2,3	0
15V	15V	0V	5V	high imp	LIN1,2,3	HIN1,2,3
15V	15V	>VITRIP	5V	0 (note 2)	0	0
15V	15V	0V	0V	high imp	0	0

**Note:** A shoot-through prevention logic prevents LO1,2,3 and HO1,2,3 for each channel from turning on simultaneously.

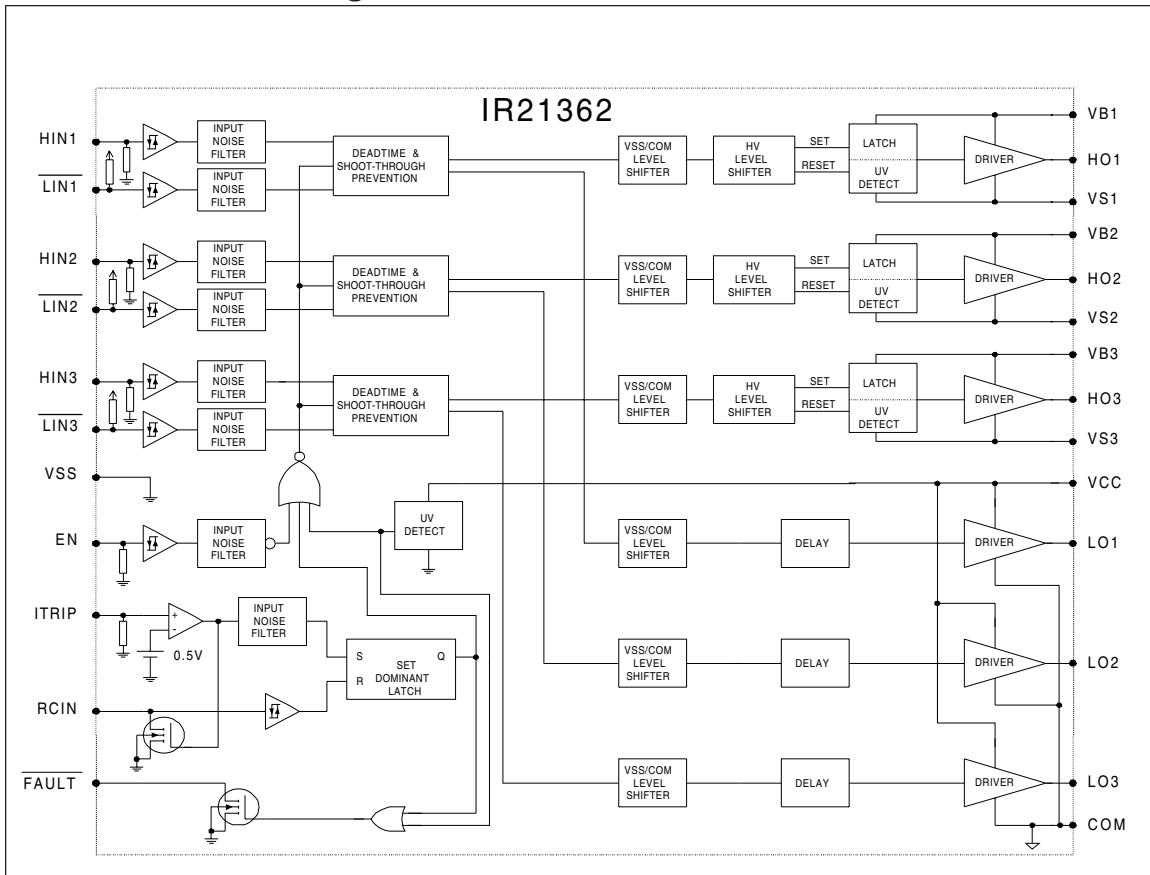
**Note 1:** UVCC is not latched, when  $VCC > UVCC$ , FAULT returns to high impedance.

**Note 2:** When ITRIP  $< V_{ITRIP}$ , FAULT returns to high-impedance after RCIN pin becomes greater than 8V (@  $VCC = 15V$ )

## Functional Block Diagram

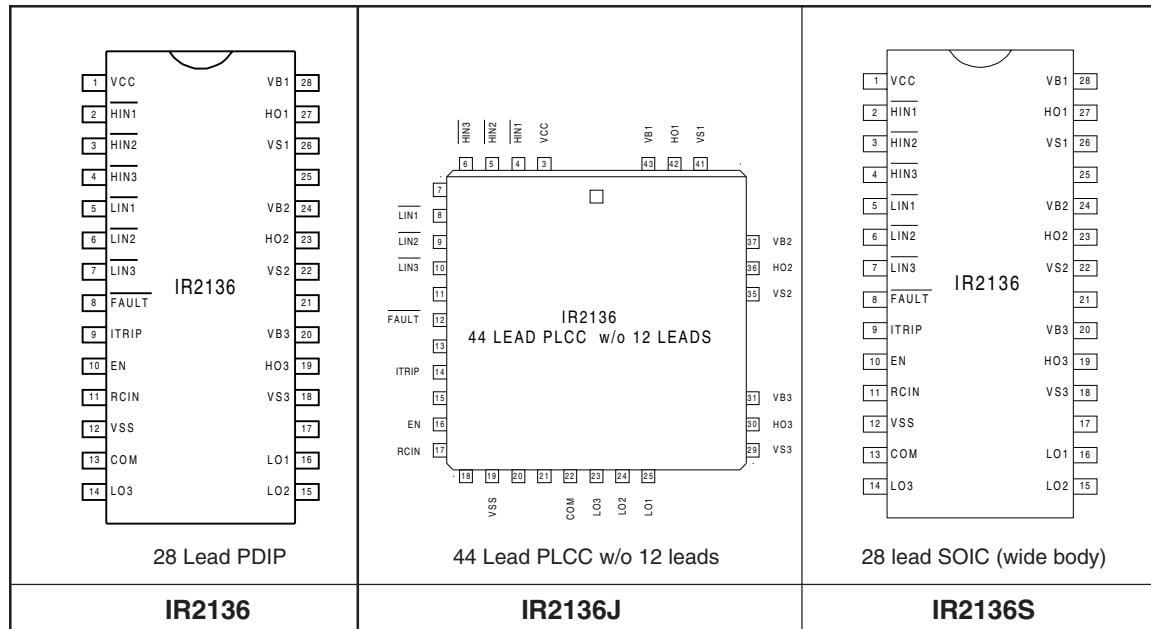


## Functional Block Diagram



## Lead Definitions

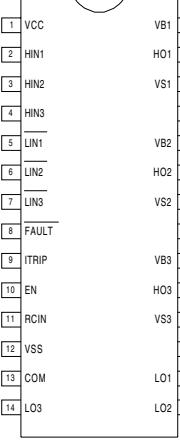
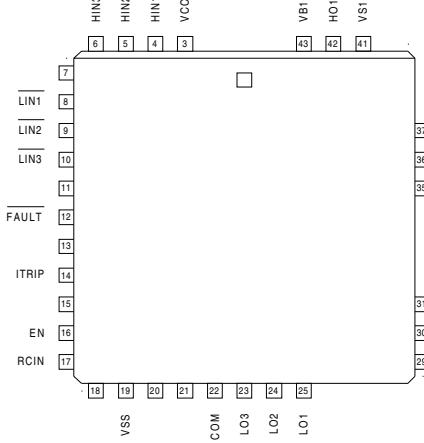
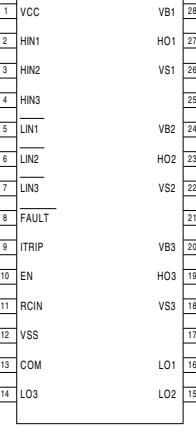
Symbol	Description
V <sub>CC</sub>	Low side and logic fixed supply
V <sub>SS</sub>	Logic Ground
HIN1,2,3	Logic inputs for high side gate driver outputs (HO1,2,3), out of phase (IR2136)
HIN1,2,3	Logic inputs for high side gate driver outputs (HO1,2,3), in phase (IR21362)
LIN1,2,3	Logic inputs for low side gate driver outputs (LO1,2,3), out of phase
FAULT	Indicates over-current (ITRIP) or low-side undervoltage lockout has occurred. Negative logic, open-drain output
EN	Logic input to enable I/O functionality. Positive logic, i.e. I/O logic functions when ENABLE is high. No effect on FAULT and not latched
ITRIP	Analog input for overcurrent shutdown. When active, ITRIP shuts down outputs and activates FAULT and RCIN low. When ITRIP becomes inactive, FAULT stays active low for an externally set time T <sub>FLTCLR</sub> , then automatically becomes inactive (open-drain high impedance).
RCIN	External RC network input used to define FAULT CLEAR delay, T <sub>FLTCLR</sub> , approximately equal to R*C. When RCIN>8V, the FAULT pin goes back into open-drain high-impedance
COM	Low side gate driver return
V <sub>B1,2,3</sub>	High side floating supply
HO1,2,3	High side gate driver outputs
V <sub>S1,2,3</sub>	High voltage floating supply returns
LO1,2,3	Low side gate driver output



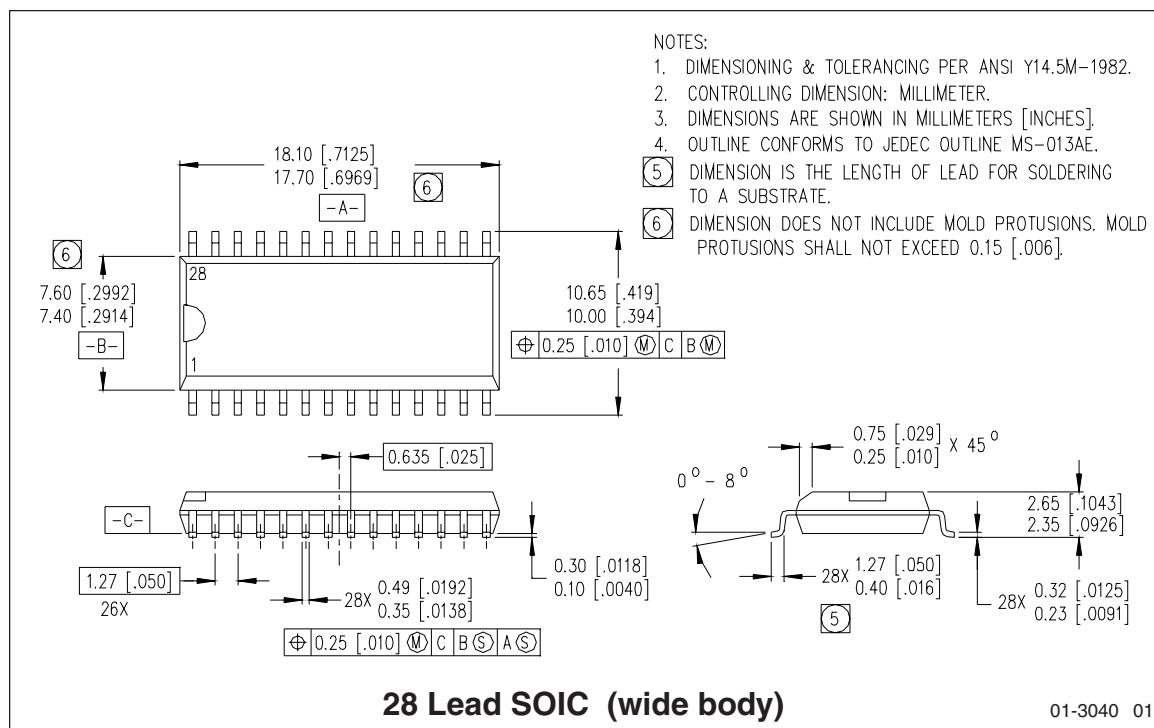
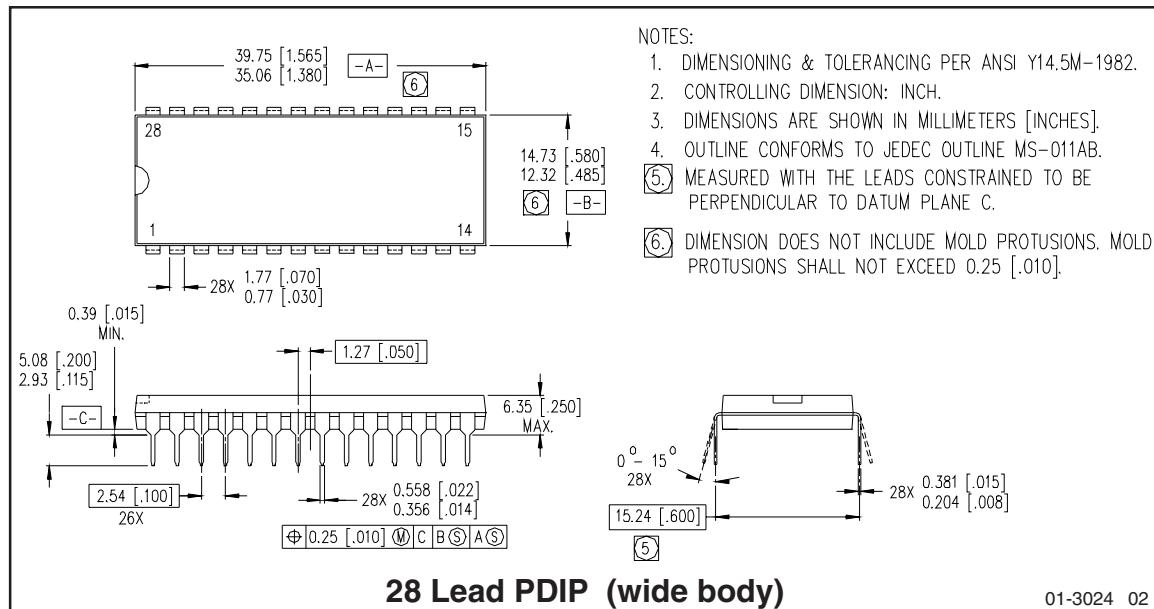
# IR2136/IR21362

## ADVANCE INFORMATION

International  
**IR** Rectifier

		
28 Lead PDIP	44 Lead PLCC w/o 12 leads	28 lead SOIC (wide body)
<b>IR21362</b>	<b>IR21362J</b>	<b>IR21362S</b>

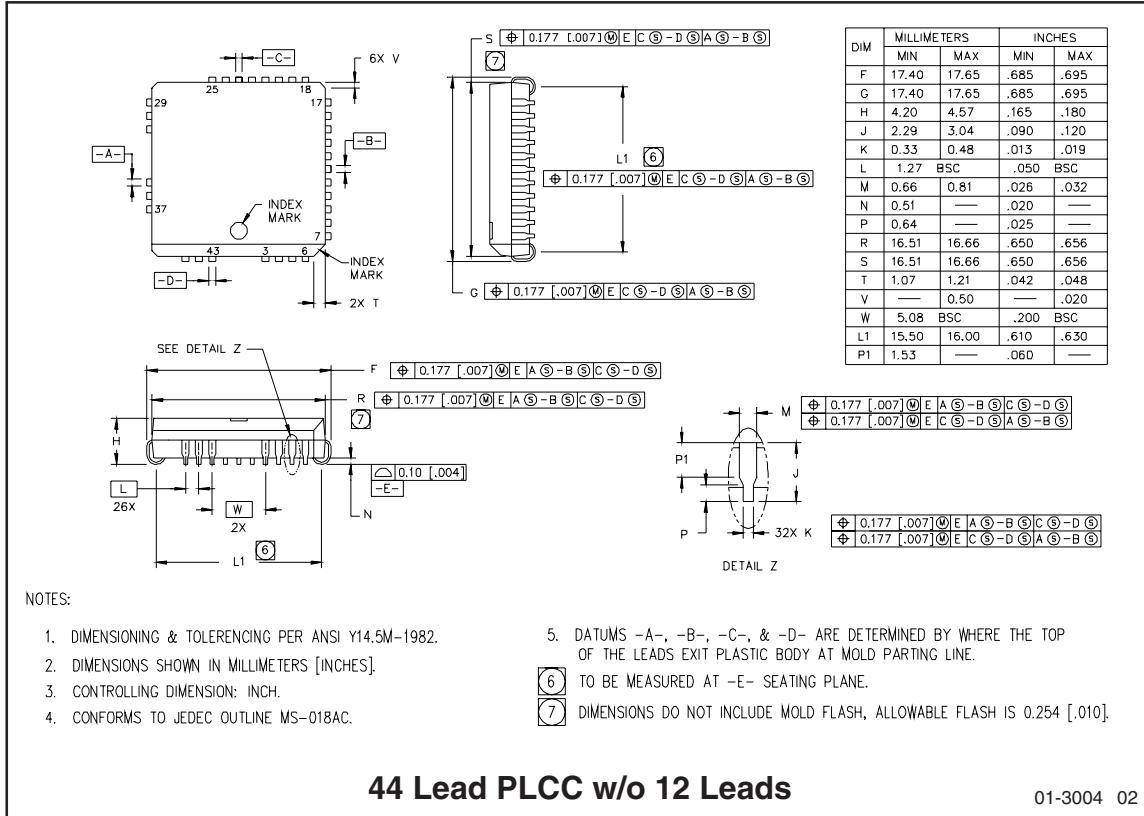
## Package Dimensions



# IR2136/IR21362

## **ADVANCE INFORMATION**

International  
**IR** Rectifier



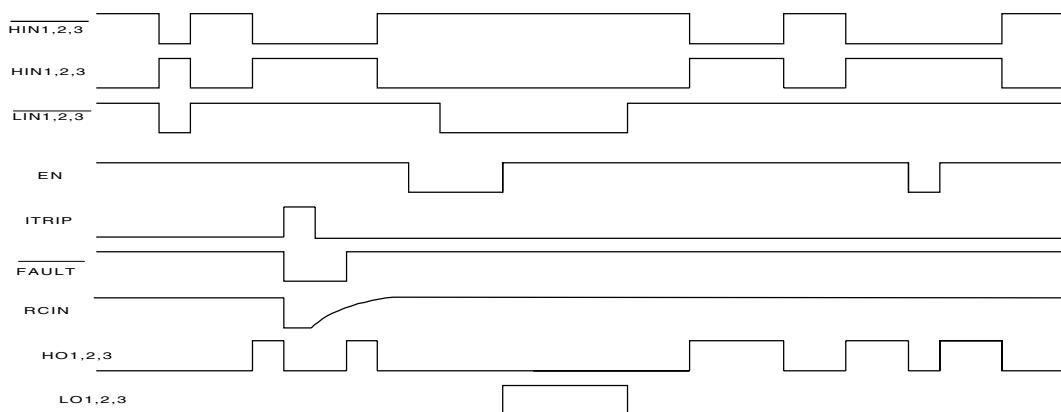


Figure 1. Input/Output Timing Diagram

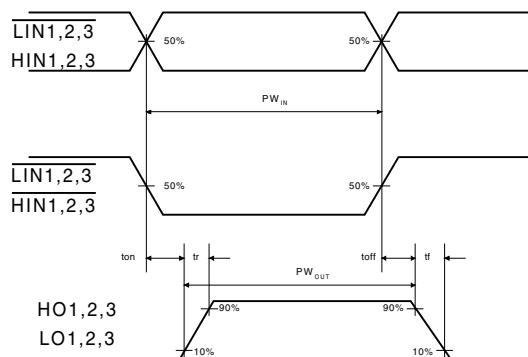


Figure 2. Switching Time Waveforms

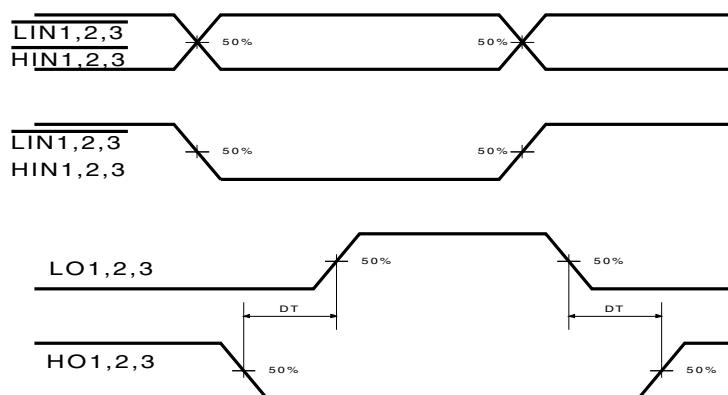


Figure 3. Internal Deadtime Timing Waveforms

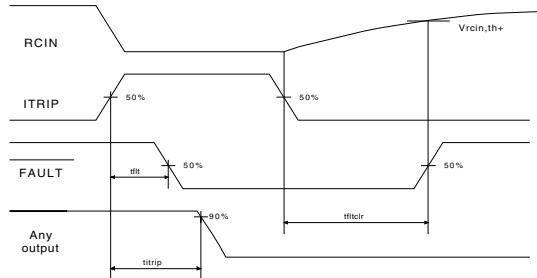


Figure 4. ITRIP/RCIN Timing Waveforms

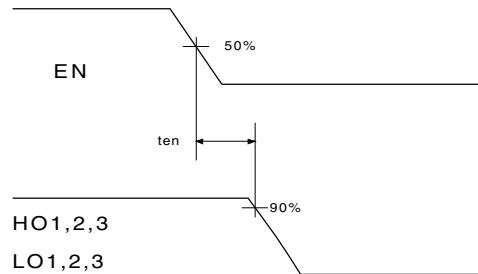


Figure 5. Output Enable Timing Waveform

International  
**IR** Rectifier

**WORLD HEADQUARTERS:** 233 Kansas St., El Segundo, California 90245 Tel: (310) 252-7105

**IR GREAT BRITAIN:** Hurst Green, Oxted, Surrey RH8 9BB, UK Tel: ++ 44 1883 732020

**IR JAPAN:** K&H Bldg., 2F, 30-4 Nishi-Ikebukuro 3-Chome, Toshima-Ku, Tokyo, Japan 171-0021 Tel: 8133 983 0086

**IR HONG KONG:** Unit 308, #F, New East Ocean Centre, No. 9 Science Museum Road, Tsimshatsui East, Kowloon,

Hong Kong Tel: (852) 2803-7380

*Data and specifications subject to change without notice. 1/5/2000*